

# HD74CDCV857A

# 2.5-V Phase-lock Loop Clock Driver

REJ03D0136-0300Z (Previous ADE-205-693B (Z)) Rev.3.00 Oct.09.2003

### **Description**

The HD74CDCV857A is a high-performance, low-skew, low-jitter, phase locked loop clock driver. It is specifically designed for use with DDR (Double Data Rate) synchronous DRAMs.

#### **Features**

- DDR333 / PC2700-Compliant, also meets DDR266 / PC2100 requirement.
- Supports 60 MHz to 170 MHz operation range
- Distributes one differential clock input pair to ten differential clock outputs pairs
- Supports spread spectrum clock requirements meeting the PC100 SDRAM registered DIMM specification
- External feedback pins (FBIN, FBIN) are used to synchronize the outputs to the clock input
- Supports 2.5V analog supply voltage (AV<sub>CC</sub>), and 2.5 V V<sub>DDQ</sub>
- No external RC network required
- Sleep mode detection
- 48pin TSSOP (Thin Shrink Small Outline Package)

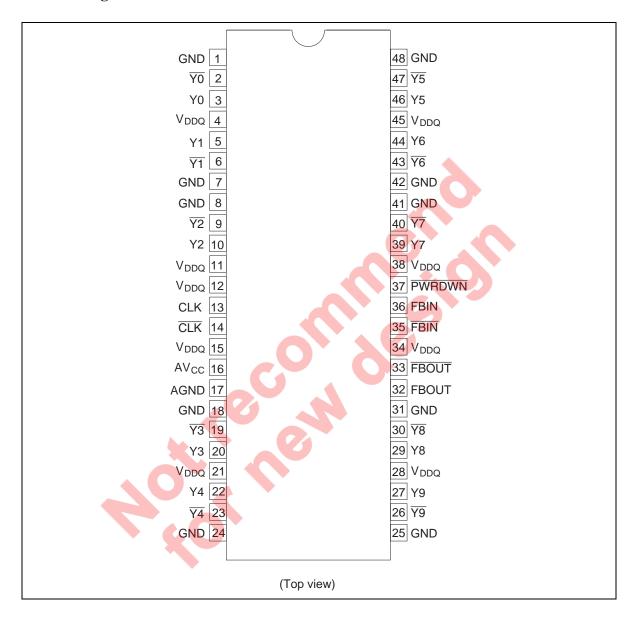
#### **Function Table**

Inputs				:	Output	ts			_	
AVCC	PWRDWN	CLK	CLK	:	Υ	Ÿ	FBOUT	<b>FBOUT</b>	:	PLL
GND	H (	L	Н	:	L	Н	L	Н	:	Bypassed / off *1
GND	Н	H	L	:	Н	L	Н	L	:	Bypassed / off *1
Χ	L	L	Н	:	Z	Z	Z	Z	:	off
Χ	L	Н	L	:	Z	Z	Z	Z	:	off
2.5 V	Н	L	Н	:	L	Н	L	Н	:	on
2.5 V	Н	Н	L	:	Н	L	Н	L	:	on
2.5 V	Χ	Input clock fr	equency	:	Z	Z	Z	Z	:	off
		60 to 170 MH	$dz \rightarrow 0 MHz$							

H: High level
L: Low level
X: Don't care
Z: High impedance

Notes: 1. Bypassed mode is used for RENESAS test mode.

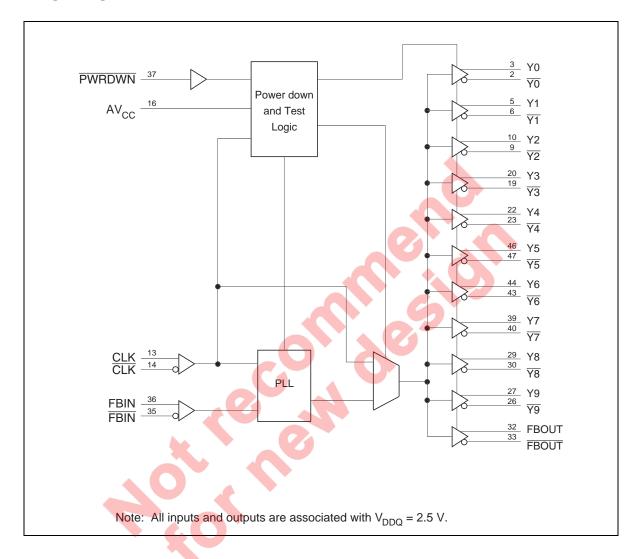
# **Pin Arrangement**



# **Pin Function**

Pin name	No.	Туре	Description					
AGND	17	Ground	Analog ground. AGND provides the ground reference for the analog circuitry.					
AV <sub>cc</sub>	16	Power	Analog power supply. $AV_{CC}$ provides the power reference for the analog circuitry. In addition, $AV_{CC}$ can be used to bypass the PLL for test purposes. When $AV_{CC}$ is strapped to ground, PLL is bypassed and CLK is buffered directly to the device outputs. This bypass mode is used for RENESAS test.					
CLK, CLK	13, 14	l Differential input	Clock input. CLK provides the clock signal to be distributed by the HD74CDCV857A clock driver. CLK is used to provide the reference signal to the integrated PLL that generates the clock output signals. CLK must have a fixed frequency and fixed phase for the PLL to obtain phase lock. Once the circuit is powered up and a valid CLK signal is applied, a stabilization time is required for the PLL to phase lock the feedback signal to its reference signal.					
FBIN, FBIN	35, 36	I Differential input	Feedback input. FBIN provides the feedback signal to the internal PLL. FBIN must be hard-wired to FBOUT to complete the PLL. The integrated PLL synchronizes CLK and FBIN so that there is nominally zero phase error between CLK and FBIN.					
FBOUT, FBOUT	32, 33	O Differential output	Feedback output. FBOUT is dedicated for external feedback. It switches at the same frequency as CLK. When externally wired to FBIN, FBOUT completes the feedback loop of the PLL.					
PWRDWN	37		Output bank enable. PWRDWN is the output enable for all outputs. When PWRDWN is low, VCO will stop and all outputs are disabled to a high impedance state. When PWRDWN will be returned high, PLL will re-synchroniz to CLK frequency and all outputs are enabled.					
GND	1, 7, 8, 18, 24, 25, 31, 41, 42, 48	Ground	Ground					
V <sub>DDQ</sub>	4, 11, 12, 15, 21, 28, 34, 38, 45	Power	Power supply					
Υ	3, 5, 10, 20, 22, 27, 29, 39, 44, 46	O Differential output	Clock outputs. These outputs provide low-skew copies of CLK.					
Y	2, 6, 9, 19, 23, 26, 30, 40, 43, 47	O Differential output	Clock outputs. These outputs provide low-skew copies of $\overline{\text{CLK}}$ .					

# Logic Diagram



# **Absolute Maximum Ratings**

Item	Symbol	Ratings	Unit	Conditions
Supply voltage	$V_{DDQ}$	-0.5 to 3.6	V	
Input voltage	Vı	-0.5 to V <sub>DDQ</sub> +0.5	V	
Output voltage *1	Vo	$-0.5$ to $V_{DDQ}$ +0.5		
Input clamp current	I <sub>IK</sub>	<b>-</b> 50	mA	V <sub>I</sub> < 0
Output clamp current	lok	<b>-</b> 50	mA	V <sub>O</sub> < 0
Continuous output current	Io	±50	mA	$V_O = 0$ to $V_{DDQ}$
Supply current through each $V_{\text{DDQ}}$ or GND	$I_{VDDQ}$ or $I_{GND}$	±100	mA	_
Maximum power dissipation at Ta = 55°C (in still air)		0.7	W	
Storage temperature	T <sub>stg</sub>	-65 to +150	°C	

#### Notes:

Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute maximum rated conditions for extended periods may affect device reliability.

1. The input and output negative voltage ratings may be exceeded if the input and output clamp current ratings are observed.



### **Recommended Operating Conditions**

Item	Symbol	Min	Тур	Max	Unit	Conditions	Notes
Output supply voltage	$V_{DDQ}$	2.3	2.5	2.7	V		
Supply voltage	AV <sub>CC</sub>	V <sub>DDQ</sub> -0.12	$V_{DDQ}$	2.7	V		
DC input signal voltage	V <sub>IN</sub>	-0.3	_	V <sub>DDQ</sub> +0.3	V	All pins	1
High level input voltage	$V_{IHG}$	1.7	_	V <sub>DDQ</sub> +0.3	V	PWRDWN input pin	
Low level input voltage	$V_{ILG}$	-0.3	_	0.7	V	PWRDWN input pin	
Input differential voltage	$V_{\text{ID}}$	0.36	_	V <sub>DDQ</sub> +0.6	V		3
Output differential voltage	$V_{\overline{O}D}$	0.70	_	V <sub>DDQ</sub> +0.6	V		
Input differential-pair cross voltage	$V_{IX}$	V <sub>DDQ</sub> /2 -0.2	_	V <sub>DDQ</sub> /2 +0.2	V		2, 3
Output differential-pair cross voltage	V <sub>OX</sub>	V <sub>DDQ</sub> /2 -0.15	-	V <sub>DDQ</sub> /2 +0.15	V		2, 3
Output current	I <sub>OH</sub>	_	- (	-12	mA		
	I <sub>OL</sub>	_	-	12	mA		
Input clock slew rate	t <sub>SL(I)</sub>	1	-	4	V/ns	20% - 80%	3
Operating temperature	Ta	0	_	70	°C		3

Notes: Inputs pins must be prevent from floating.

Feedback inputs (FBIN, FBIN) may float when the device is in low power mode.

- 1. DC input signal voltage specifies the allowable dc execution of differential input.
- 2. Differential cross point voltage is expected to track variations of V<sub>DDQ</sub> and is the voltage at which the differential signals must be crossing. (See figure1)
- 3. Guaranteed by design, not 100% tested in production.

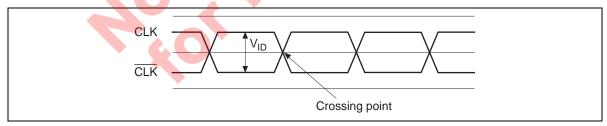


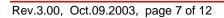
Figure 1 Differential input levels

### **Electrical Characteristics**

Item		Symbol	Min	Typ *1	Max	Unit	Test Conditions	Notes
Input clamp voltage	CLK, CLK FBIN, FBIN, G	$V_{IK}$	_	_	-1.2	V	$I_1 = -18 \text{ mA},$ $V_{DDQ} = 2.3 \text{ V}$	
Output voltage		V <sub>OH</sub>	V <sub>DDQ</sub> -0.1	_	_	V	$I_{OH} = -100 \mu A,$ $V_{DDQ} = 2.3 \text{ to } 2.7 \text{ V}$	
			1.7	_		_	$I_{OH} = -12 \text{ mA},$ $V_{DDQ} = 2.3 \text{ V}$	
		V <sub>OL</sub>	_	_	0.1	_	$I_{OL} = 100 \mu\text{A},$ $V_{DDQ} = 2.3 \text{ to } 2.7 \text{ V}$	
			_	_	0.6	<u>-</u>	$I_{OL} = 12 \text{ mA},$ $V_{DDQ} = 2.3 \text{ V}$	
Input current		lı	<b>–</b> 10	_	10	μΑ	$V_1 = 0 \text{ V to } 2.7 \text{ V},$ $V_{DDQ} = 2.7 \text{ V}$	
Input capacit	ance	Cı	_	2.5	-	pF	CLK and CLK, FBIN and FBIN	2
Supply current		DI <sub>CC</sub>	_	200	350	mA	f = 170 MHz,	3
		Alcc	_	9	12		$V_{DDQ} = AV_{CC} = 2.7 \text{ V}$	
Supply curred down mode	nt in power	I <sub>CCpd</sub>	_	100	200	μA		

Note: 1. For conditions shown as Min or Max, use the appropriate value specified under recommended operating conditions.

- 2. Guaranteed by design, not 100% tested in production.
- 3. All outputs are loaded as shown in Figure 2.





#### **Switching Characteristics**

Item	Symbol	Min	Тур	Max	Unit	<b>Test Conditions</b>	Notes
Period jitter	t <sub>PER</sub>	<b>–</b> 75	_	75	ps	See figure 6, 9	7, 8
Half period jitter	t <sub>HPER</sub>	-100	_	100	ps	See figure 7, 9	8, 10
Cycle to cycle jitter	t <sub>CC</sub>	<b>-</b> 75	_	75	ps	See figure 5, 9	10
Static phase offset	t <sub>SPE</sub>	<b>-</b> 50	_	50	ps	See figure 3, 9	4, 5, 9, 10
Output clock skew	t <sub>sk</sub>	_	_	100	ps	See figure 4, 9	
Operating clock frequency	f <sub>CLK(O)</sub>	60	_	200	MHz	See figure 9	1, 2
Application clock frequency	f <sub>CLK(A)</sub>	80	167	170	MHz	See figure 9	1, 3
Input clock duty cycle	t <sub>DC</sub>	40	_	60	%		10
Output clock Slew rate	t <sub>SL(O)</sub>	1.0	_	2.0	V/ns	See figure 9 20% – 80%	
PLL stabilization time	t <sub>STAB</sub>	_	_	0.1	ms	See figure 9	6, 10
SSC modulation frequency		30	_	50	KHz		10
SSC clock input frequency deviation		0.00		-0.50	%	7	10
PLL loop bandwidth		_	3	-	MHz		10

Notes: 1. The PLL must be able to handle spread spectrum induced skew (the specification for this frequency modulation can be found in the latest Intel PC100 Registered DIMM specification)

- 2. Operating clock frequency indicates a range over which the PLL must be able to lock, but in which it is not required to meet the other timing parameters.
- 3. Application clock frequency indicates a range over which the PLL must meet all timing parameters.
- 4 Assumes equal wire length and loading on the clock output and feedback path.
- 5. Static phase offset does not include jitter.
- 6. Stabilization time is the time required for the integrated PLL circuit to obtain phase lock of its feedback signal to its reference signal after power up.
- 7. Period jitter defines the largest variation in clock period, around a nominal clock period.
- 8. Period jitter and half-period jitter are independent from each other.
- 9. Conditions at  $V_{DDQ} = 2.5 \text{ V}$ ,  $Ta = 25^{\circ}\text{C}$ .
- 10. Guaranteed by design, not 100% tested in production.

Differential clock outputs are directly terminated by a 120  $\Omega$  resistor. Figure 2 is typical usage conditions of outputs load.

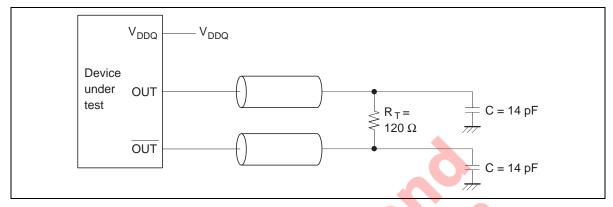


Figure 2 Differential signal using direct termination resistor

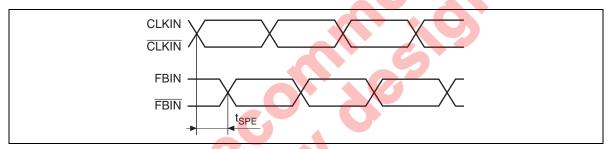


Figure 3 Static phase offset

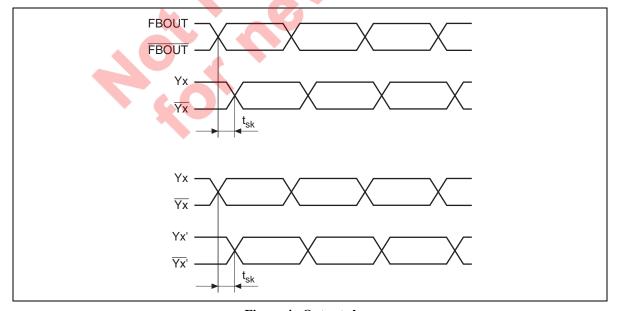


Figure 4 Output skew

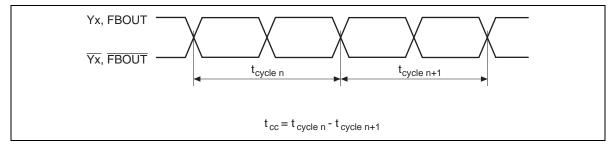


Figure 5 Cycle to cycle jitter

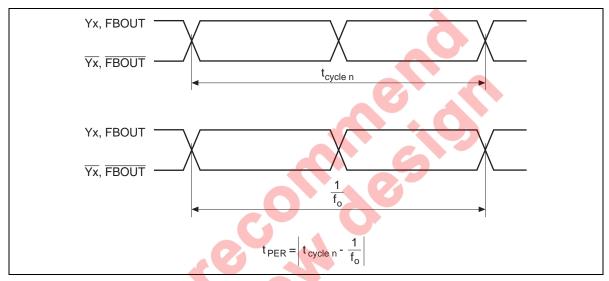


Figure 6 Period jitter

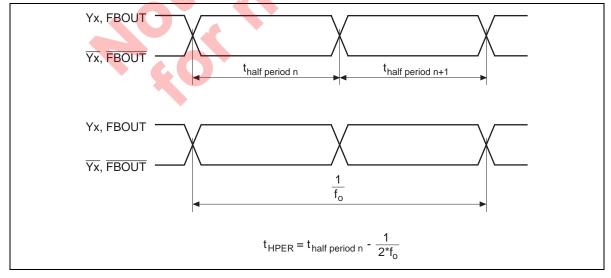


Figure 7 Half period jitter

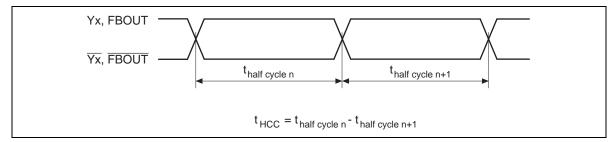


Figure 8 Half cycle to cycle jitter

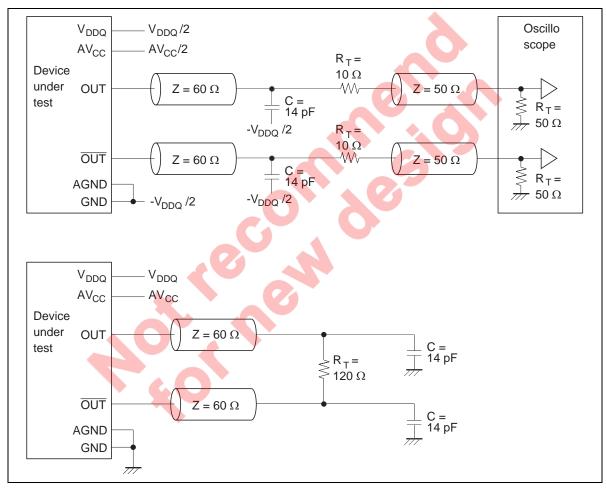
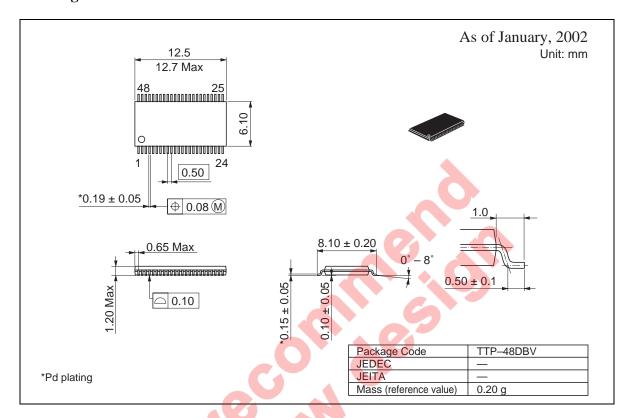


Figure 9 Output load test circuit

# **Package Dimensions**



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